TOSHIBA Photocoupler GaAłAs IRED & Photo IC

TLP551

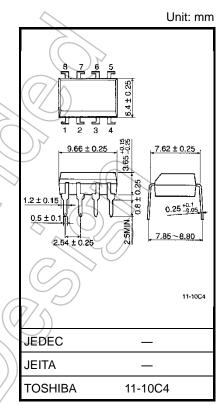
Controllers Interfaces for Calculators and Control Devices Noise Attenuation in Measurement and System Devices Signal Transmission between circuits of different potential

The TOSHIBA TLP551 consists of a GaAlAs high-output light emitting diode and a high speed detector of one chip photo diode-transistor. This unit is 8-lead DIP.

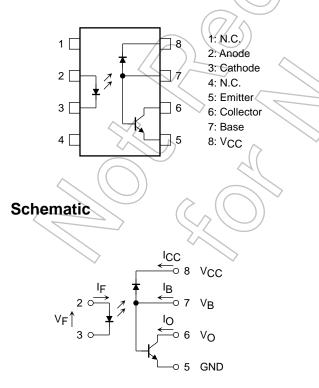
TLP551 has an internal base connection. This base pin should be used for analog application or enable operation.

- Isolation voltage: 2500 V_{rms} (min)
- Switching speed: $t_{pHL} = 0.5 \ \mu s \ (typ.)$ $t_{pLH} = 0.6 \ \mu s \ (typ.)$
 - $(R_{L} = 1.9 \text{ k}\Omega)$
- TTL compatible
- If the base pin is open, external noise will cause interference to the output signal. In this scenario, TLP550 will be recommended.
- UL recognized: UL1577, file no. E67349
- cUL approved :CSA Component Acceptance Service No. 5A, File No.E67349

Pin Configurations (top view)



Weight: 0.54 g (typ.)



Start of commercial production 1981-09

Absolute Maximum Ratings (Ta = 25°C)

	Characteristics	Symbol	Rating	Unit	
	Forward current	١F	25	mA	
	Forward current derating (Ta≥ 70 °C)	Δ IF/ Δ Ta	-0.8	mA/°C	
	Pulse forward current (Note 1)	IFP	50	mA 🔇	
ED	Pulse forward current derating (Ta≥ 70 °C)	ΔIFP/ΔTa	-1.6	mA/°C	
Щ	Peak transient forward current (Note 2)	IFPT	1	А	$\sum r^{2}$
	Reverse voltage	V _R	5	Ma	
	Diode power dissipation	PD	45	mVV))
	Diode power dissipation derating (Ta \ge 70 °C)	$\Delta P_{D} / \Delta Ta$	-0.9	mW/ºC	
	Output current	IO	8	mA	
	Peak output current	IOP	16	mA	
	Output voltage	VO	-0.5 to 15	v	
Detector	Supply voltage	VCC	-0.5 to 15	> v	\leq
Dete	Base current	ΙB	5	mA	
	Emitter-base reverse voltage	VEB	5	V	
	Output power dissipation	Po	100	mW	\sim
	Output power dissipation derating (Ta≥ 70 °C)	$\Delta P_0 / \Delta Ta$	-1.8	mW/°C	\mathcal{O}
Ope	erating temperature range	Topr	✓ –55 to 100		
Storage temperature range		Tstg	-55 to 125	3°	
Lea	d solder temperature (10 s) (Note 3)	T _{sol}	260	℃	
Isol	ation voltage (AC, 60 s, R.H. \leq 60%) (Note 4)	BVS	2500	V _{rms}	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: 50% duty cycle, 1 µs pulse width.

Note 2: Pulse width \leq 1 μ s, 300 pps.

together.

Note 3: Soldering portion of lead: up to 2 mm from body of the device.

Note 4: Device considered a two-terminal device: Pins 1, 2, 3 and 4 shorted together and pins 5, 6, 7 and 8 shorted

Electrical Characteristics (Ta = 25°C)

	Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
	Forward voltage	VF	IF = 16 mA	1.45	1.65	1.85	V
LED	Forward voltage temperature coefficient	∆V _F /∆Ta	I _F = 16 mA	2	-2		mV/°C
	Reverse current	IR	$V_{R} = 5 V$	X	-	10	μΑ
	Capacitance between terminal	С _Т	V _F = 0 V, f = 1 MHz	(\in)	60	_	pF
		IOH(1)	$I_F = 0 \text{ mA}, V_{CC} = V_O = 5.5 \text{ V}$		3	500	nA
Detector	High level output current	IOH(2)	$I_F = 0 \text{ mA}, V_{CC} = V_O = 15 V$	/	—	5	μΑ
		IOH	$I_F = 0 \text{ mA}, V_{CC} = V_O = 15 \text{ V}, \text{ Ta} = 70^{\circ}\text{C}$))	—	50	μΑ
	High level supply voltage	Іссн	$I_F = 0 \text{ mA}, V_{CC} = 15 \text{ V}$	$\geq -$	0.01	1	μΑ

Coupled Electrical Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition Min	Тур.	Max	Unit
		$I_F = 16 \text{ mA}, V_{CC} = 4.5 \text{ V}, V_O = 0.4 \text{ V}$ (10)	30	/ _	
Current transfer ratio	^I O ^{/I} F	Rank: O	30	_	%
		$I_F = 16 \text{ mA}, V_{CC} = 4.5 \text{ V}, V_O = 0.4 \text{ V}$ 5) –	_	70
		Ta = 0 to 70°C Rank: 0 15		_	
Low level output voltage	VOL	$ F = 16 \text{ mA}, V_{CC} = 4.5 \text{ V}, I_{O} = 1.1 \text{ mA} $ (Rank O: $I_{O} = 2.4 \text{ mA}$)	_	0.4	V

Isolation Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Capacitance (input-output)	Cs	V _S = 0 V, f = 1 MHz	_	0.8	_	pF
Resistance (input-output)	RS	$V_{S} = 500 V_{DC}, R.H. \le 60\%$ (Note 1)	5×10^{10}	10 ¹⁴	_	Ω
		AC, 60 s	2500	_	_	V
Isolation voltage	D BVS	AC, 1 s, in oil	—	5000	— V _{rm}	
		DC, 60 s, in oil	_	5000	_	V _{dc}

Note 1: Device considered a two-terminal device: Pins 1, 2, 3 and 4 shorted together and pins 5, 6, 7 and 8 shorted together.



Switching Characteristics (Ta = 25°C, V_{CC} = 5 V)

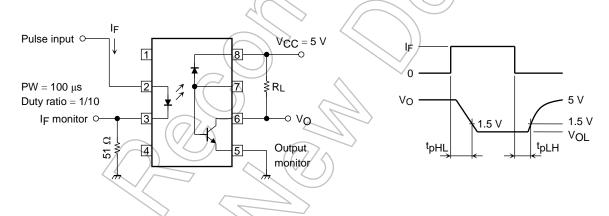
Characteristics	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
			$I_F = 16 \text{ mA}, R_L = 4.1 \text{ k}\Omega$	_	0.3	0.8	
Propagation delay time (H \rightarrow L)	^t pHL	1	$I_F = 16 \text{ mA}, R_L = 1.9 \text{ k}\Omega$ (Rank O)	I	0.5	0.8	μs
			$I_F = 16 \text{ mA}, R_L = 4.1 \text{ k}\Omega$	\searrow	1	2	
Propagation delay time (L \rightarrow H)	^t pLH	1	IF = 16 mA, RL = 1.9 kΩ (Rank O)	E	0.6	1.2	μS
Common mode transient immunity at logic high output	CMH	2	$I_{F} = 0 \text{ mA}, V_{CM} = 200 \text{ V}_{p\text{-}p}$ $R_{L} = 4.1 \text{ k}\Omega$ $(\text{Rank O: } R_{L} = 1.9 \text{ k}\Omega)$	S)	400	_	V/µs
Common mode transient immunity at logic low output	CML	2	$I_F = 16$ mA, V _{CM} = 200 V _{p-p} R _L = 4.1 kΩ (Rank O: R _L = 1.9 kΩ)	> _	-1000	/	V/µs

Note: CM_H: The maximum tolerable rate of rise of the common mode voltage to ensure that the output will remain in the high output state (i.e., $V_O > 2.0 V$). Measured in volts per microsecond (V/µs).

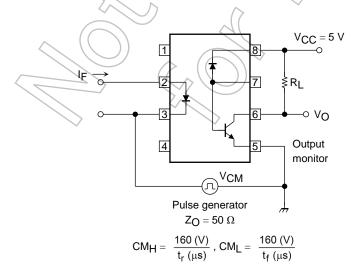
CML: The maximum tolerable rate of fall of the common mode voltage to ensure that the output will remain in the low output state (i.e., $V_O < 0.8 V$). Measured in volts per microsecond (V/µs).

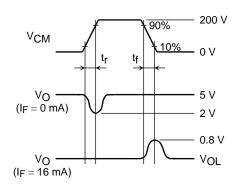
Maximum electrostatic discharge voltage for any pins: 100 V (C = 200 pF, R = 0).

Test Circuit 1: Switching Time Test Circuit

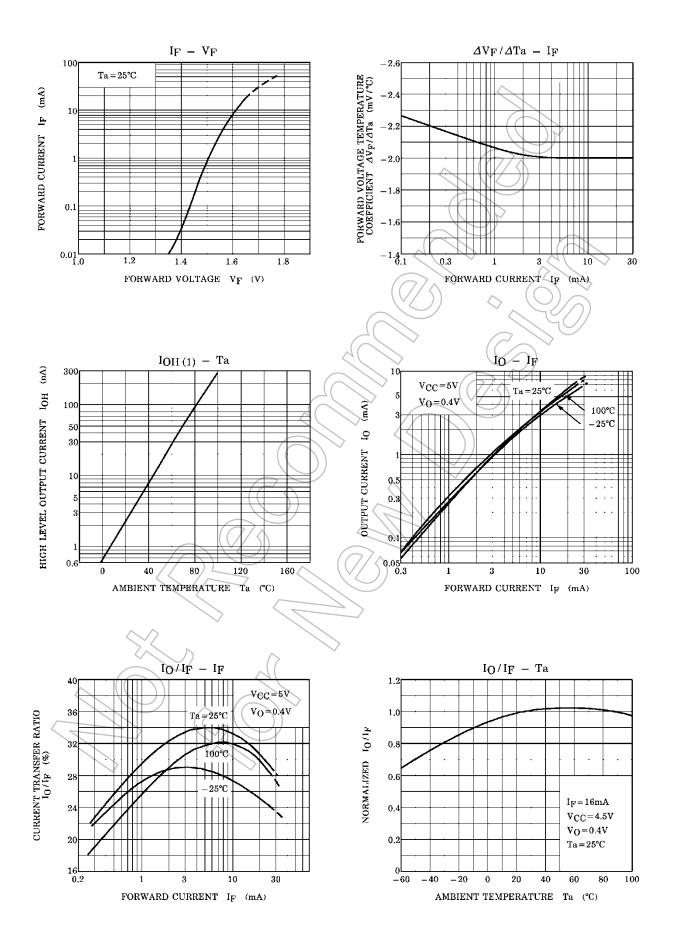


Test Circuit 2: Common Mode Noise Immunity Test Circuit

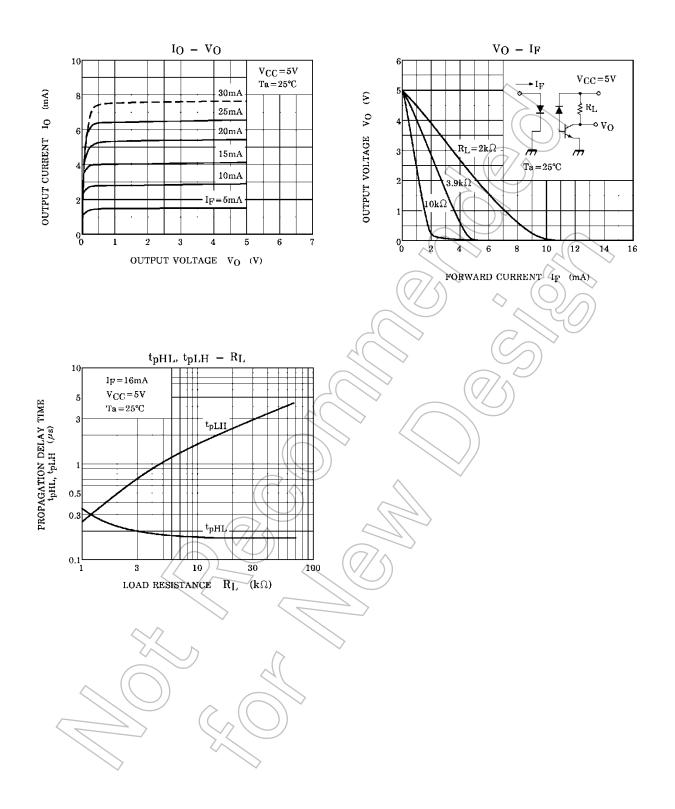




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